## Applicant(s)/Patent Under Application/Control No. Reexamination 10/802,910 FUKUNARI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 KWOK W. LEE 2195 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification MM-YYYY Country Code-Number-Kind Code 12-2003 709/100 US-2003/0233387 Watanabe et al. Α US-В US-С US-D US-Ε US-F US-G US-Н

## FOREIGN PATENT DOCUMENTS

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